# 2SD2441

## Silicon NPN epitaxial planar type

### For low-frequency output amplification

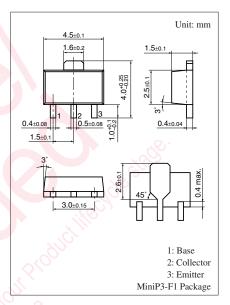
#### ■ Features

 Mini Power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing

## $\blacksquare$ Absolute Maximum Ratings $T_a = 25 ^{\circ}C$

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	10	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	10	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	7	V	
Collector current	$I_{C}$	1.5	A	
Peak collector current	$I_{CP}$	2	A	
Collector power dissipation *	$P_{C}$	1	W	
Junction temperature	T <sub>j</sub>	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	

Note) \*: Printed circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion



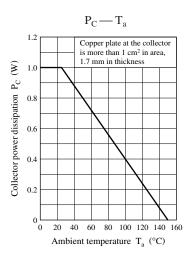
Marking Symbol: 1V

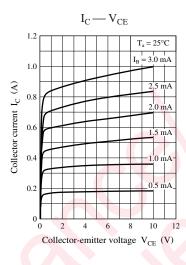
### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

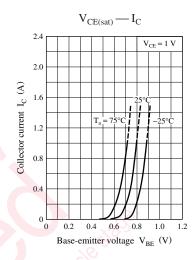
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_C = 10 \mu\text{A}, I_E = 0$	10	0///		V
Collector-emitter voltage (Base open)	$V_{CEO}$	$I_C = 1 \text{ mA}, I_B = 0$	10	0-		V
Emitter-base voltage (Collector open)	$V_{\rm EBO}$	$I_E = 10 \mu\text{A},  I_C = 0$	7			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 7 \text{ V}, I_{E} = 0$			1	μΑ
Forward current transfer ratio	$h_{FE}$	$V_{CE} = 1 \text{ V}, I_{C} = 400 \text{ mA}$	200		700	_
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = 1 \text{ A}, I_B = 25 \text{ mA}$		0.17	0.25	V
Transition frequency	$f_T$	$V_{CB} = 6 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		190		MHz
Collector output capacitance (Common base, input open circuited)	C <sub>ob</sub>	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		50		pF
Forward voltage *	V <sub>F</sub>	$I_F = 500 \text{ mA}$			1.3	pF

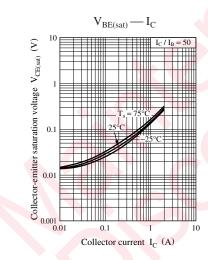
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

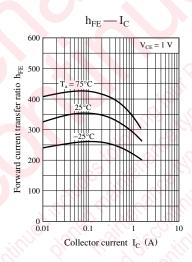
<sup>2. \*:</sup> Applicable to the built-in diode.

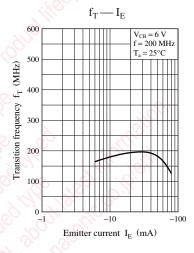


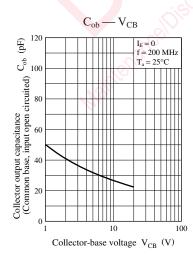












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